

<b>Notice of References Cited</b>	Application/Control No. 10/566,116	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner Weiping Zhu	Art Unit 1742	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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	D	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Fan et al., "Deformation Behavior of Zr-Based Bulk Nanocrystalline Amorphous Alloys", Physical Review B, volume 61, number 6, R3761-R3763, February 1, 2000-II.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.